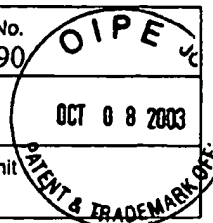
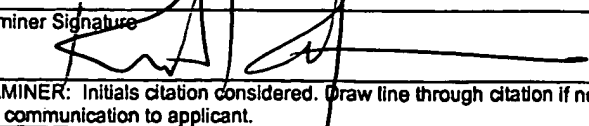


Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>15540-011001</b>	Application No. <b>10/660,790</b>
		Applicant <b>Stefan Fliss</b>	
	Filing Date <b>September 12, 2003</b>	Group Art Unit	



U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>R</i>	AA	4,691,106	Sept. 1, 1987	Hyun et al.	—	—	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>R</i>	AB	Dowden, S. et al., "Reflectometer for fast measurements of mirror reflectivity," Measurement Science and Technology, IOP Publishing, Bristol, GB, Bd. 8, Nr. 11, pp. 1258-1261 (1997).
<i>R</i>	AC	Takahashi H. et al., "Automatic reflectivity map measurement of high power CO <sub>2</sub> laser optics," Optics and Laser Technology, Elsevier Science Publishers BV., Amsterdam, NL, Bd. 21, Nr. 1, pp. 37-39 (1989).

Examiner Signature 	Date Considered <b>30 Sept 2003</b>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	